



JSM-IT300

New Generation JEOL Scanning Electron Microscope

- **Extended low vacuum capability as standard**
[650 Pa]
- **New charge-free scanning modes**
- **New faster, quieter, high-load stage**
[2 kg tilted to 90°]
- **Even more accessory ports**
[EDS/WDS/EBSD working distance of 10 mm]
- **High resolution frame store (5120 × 3920) as standard**
- **High reliability**